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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani
Title: Inspection System For Integrated Applications
Application No.: 10/659,556 . Filing Date: September 9, 2003
Examiner: Unknown Group Art Unit: 2877
Docket No.: TNCR.207US1 Conf. No.: 3091

Certificate of Mailing Under 37 CFR 1.8

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INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited

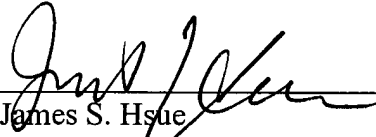
Attorney Docket No.:
TNCR.207US1

Application No.:
10/659,556

document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Respectfully submitted,


James S. Hsue
Reg. No. 29,545

6/9/04
Date

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